



AO4805

Dual P-Channel Enhancement Mode Field Effect Transistor

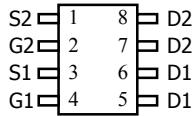
General Description

The AO4805 uses advanced trench technology to provide excellent $R_{DS(ON)}$, and ultra-low low gate charge with a 25V gate rating. This device is suitable for use as a load switch or in PWM applications.

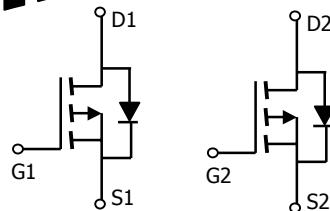
Features

V_{DS} (V) = -30V
 I_D = -12 A
 $R_{DS(ON)} < 18m\Omega$ ($V_{GS} = -20V$)
 $R_{DS(ON)} < 19m\Omega$ ($V_{GS} = -10V$)

Preliminary



SOIC-8



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum		Units
Drain-Source Voltage	V_{DS}	-30		V
Gate-Source Voltage	V_{GS}	± 25		V
Continuous Drain Current ^A	I_D	-8		A
$T_A=70^\circ C$		-6.9		
Pulsed Drain Current ^B	I_{DM}	-40		
Power Dissipation ^A	P_D	2		W
$T_A=70^\circ C$		1.44		
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150		°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$		62.5	°C/W
Steady-State			110	°C/W
Maximum Junction-to-Lead ^C	$R_{\theta JL}$		40	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units	
STATIC PARAMETERS							
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$	$T_J=55^\circ\text{C}$	-1	-5	μA	
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 25\text{V}$			± 100	nA	
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1.7	-2.5	-3	V	
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	60			A	
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-10\text{A}$		15	19	$\text{m}\Omega$	
		$V_{GS}=-20\text{V}, I_D=-10\text{A}$	$T_J=125^\circ\text{C}$	14	18		
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-10\text{A}$				S	
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.75	-1	V	
I_S	Maximum Body-Diode Continuous Current				-2.6	A	
DYNAMIC PARAMETERS							
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		2076		pF	
C_{oss}	Output Capacitance			503		pF	
C_{rss}	Reverse Transfer Capacitance			302		pF	
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		5.9		Ω	
SWITCHING PARAMETERS							
Q_g	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-12\text{A}$		37.2		nC	
Q_{gs}	Gate Source Charge			7		nC	
Q_{gd}	Gate Drain Charge			10.4		nC	
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=1.25\Omega, R_{\text{GEN}}=6\Omega$		12		ns	
t_r	Turn-On Rise Time			39		ns	
$t_{\text{D(off)}}$	Turn-Off Delay Time			48		ns	
t_f	Turn-Off Fall Time			34		ns	
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-12\text{A}, dI/dt=100\text{A}/\mu\text{s}$		33		ns	
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-12\text{A}, dI/dt=100\text{A}/\mu\text{s}$		23		nC	

A: The value of R_{0JA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R_{0JA} is the sum of the thermal impedance from junction to lead R_{0JL} and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.